

Notice of References Cited	Application/Control No. 10/775,660		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Patrick D. Niland		Art Unit 1796	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0035319	02-2004	Yeh et al.	106/31.6
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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